



Docket No.: 50090-339

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of

Takashi INBE

Serial No.: 09/960,356

Filed: September 24, 2001

For: SEMICONDUCTOR DEVICE FOR DETECTING NEUTRON, AND METHOD  
FOR THE FABRICATION

Group Art Unit: 2811

Examiner: Gene Munson

**PRELIMINARY AMENDMENT**

Commissioner for Patents  
Washington, DC 20231

Sir:

The following amendments and remarks are submitted in conjunction with the filing of a Request for Continued Examination in response to the Office Action dated November 18, 2002.

This amendment is presented in accord with the Waiver of 37 C.F.R. § 1.121 published in the Pre-OG notices on January 31, 2003.

**PATENT**

4/29/03

Adm H

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